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Introducing the new Hitachi SU8000 UHR FESEM

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For over 35 years, Hitachi has been a worldwide leader in Field Emission Microscopy surpassing all other manufacturers. Year after year each new product sets the industry standard for innovation, performance, and field proven reliability. The SU8000 is no exception. A new *Triple Detector System* provides more flexibility and optimization of signal detection to reveal surface information never seen before in any high resolution electron microscope. For the first time three high speed detectors separate, mix and control SE, low angle BSE and high angle BSE to reveal surface information and Z contrast only possible on the Hitachi SU8000 UHR FESEM.

Standard Feature

- Patented Triple Detector System
- Beam Deceleration for increased resolution and decreased radiation damage to the sample
- ExB energy filter system for enhanced signal collection and beam alignment memory
- 5 axis computer eucentric stage with quick specimen exchange and image navigation function
- Completely dry vacuum system, less than 30 second specimen exchange time
- 24.1" wide screen LCD monitor with stunning 1280 x 960 screen resolution
- Designed and manufactured in Japan with ISO 9000 standards
- Integrated PCI image archival and image processing system
- Large analytical chamber with EDS ready hardware
- Easy operation with onscreen help functions
- Fast and accurate auto functions

Call or email today for more information or to schedule a hands on demonstration

925-218-2800 (ask for Steve) or e-mail request at sales@hitachi-hta.com





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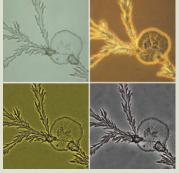
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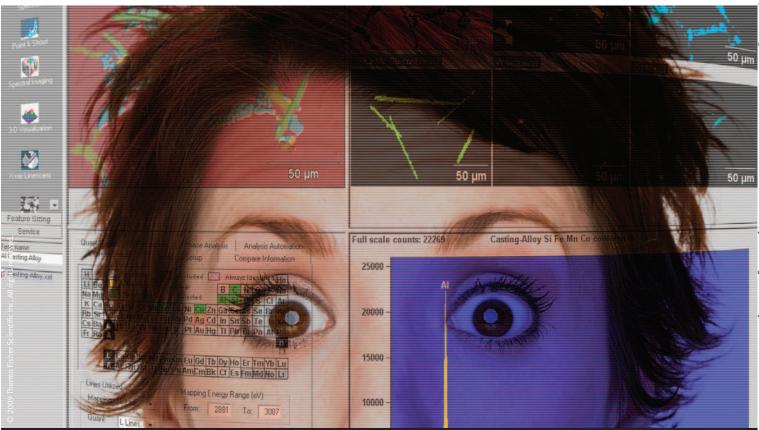
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Unstained thin-layer crystallization in four bright-field light microscopy modes. Image width = 74 µm.

See article by Piper.



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